SLFS023A - D2440, APRIL 1978 - REVISED OCTOBER 1992

- Two Precision Timing Circuits per Package
- Astable or Monostable Operation
- TTL-Compatible Output Can Sink or Source Up to 150 mA
- Active Pullup or Pulldown
- Designed to be Interchangeable With Signetics SE556, SE556C, SA556, NE556

#### **APPLICATIONS**

Precision Timer From Microseconds to Hours Pulse-Shaping Clrcuit Missing-Pulse Detector Tone-Burst Generator Pulse-Width Modulator Pulse-Position Modulator Sequential Timer Pulse Generator Time-Delay Circuit Frequency Divider Appliance Timer Industrial Controls Touch-Tone Encoder

#### SE556C FROM TI IS NOT RECOMMENDED FOR NEW DESIGNS

#### description

These devices provide monolithic, two independent timing circuits of the NE555, SA555, SE555, or SE555C type in each package. These circuits operated can be in the astable or the monostable mode with external resistor-capacitor timing control. The basic timing provided by the RC time constant may be actively controlled by modulating the bias of the control voltage input.

The threshold and trigger levels are normally two-thirds and one-third respectively of  $V_{CC}$ . These levels can be altered by use of the control voltage terminal. When the trigger input falls below trigger level, the flip-flop is set and the output goes high. If the trigger input is above the trigger level and the threshold input is above the threshold level, the flip-flop is reset and the output is low. The reset input can override all other inputs and can be used to initiate a new timing cycle. When the reset input goes low, the flip-flop is reset and the output is low, a low impedance path is provided between the discharge terminal and ground.





### functional block diagram (each timer)



RESET can override TRIG, which can override THRES.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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### description (continued)

The NE556 is characterized for operation from 0°C to 70°C. The SA556 is characterized for operation from -40°C to 85°C, and the SE556 and SE556C are characterized for operation over the full military range of -55°C to 125°C.

		PACKAGE							
T <sub>A</sub> RANGE	V <sub>thres</sub> max V <sub>CC</sub> = 15 V	SMALL OUTLINE (D)	CHIP OUTLINE (FK)	CERAMIC DIP (J)	PLASTIC DIP (N)				
0°C to 70°C	11.2 V	NE556D		NE556J					
– 40°C to 85°C	11.2 V	SA556D		SA556J	SA556N				
– 55°C to 125°C	10.6 V 11.2 V		SE556FK SE556CFK						

#### **AVAILABLE OPTIONS**

The D package is available taped and reeled. Add the suffix R to the devicetype (e.g., NE556DR).

FUNCTION TABLE									
RESET	TRIGGER VOLTAGE <sup>†</sup>	THRESHOLD VOLTAGE <sup>†</sup>	OUTPUT	DISCHARGE SWITCH					
Low	Irrelevant	Irrelevant	Low	On					
High	< 1/3 V <sub>DD</sub>	Irrelevant	High	Off					
High	> 1/3 V <sub>DD</sub>	$> 2/3 V_{DD}$	Low	On					
High	> 1/3 V <sub>DD</sub>	> 2/3 V <sub>DD</sub>	As previously established						

### FUNCTION TABLE

<sup>†</sup> Voltage levels shown are nominal.

### absollute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage, V <sub>CC</sub> (see Note 1)	
Input voltage (CONT, RESET, THRES, and T	RIG) V <sub>CC</sub>
Output current	±225 mÅ
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range: NE556	0°C to 70°C
SA556	−40°C to 85°C
SE556	SE556C –55°C to 125°C
Storage temperature range	−65°C to 150°C
Case temperature for 60 seconds: FK package	e
Lead temperature 1,6 mm (1/16 inch) from ca	se for 60 seconds: J package 300°C
Lead temperature 1,6 mm (1/16 inch) from ca	se for 10 seconds: D or N package

<sup>†</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the recommended operating conditions section of this specification is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. NOTE 1: All voltage values are with respect to network ground terminal.



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DISSIPATION RATING TABLE										
PACKAGE	TA ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING					
D	950 mW	7.6 mW/°C	608 mW	494 mW	N/A					
FK	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW					
J (NE556, SA556)	1025 mW	8.2 mW/°C	656 mW	533 mW	N/A					
J (SE556, SE556C)	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW					
N	1575 mW	12.6 mW/°C	1008 mW	891 mW	N/A					

### recommended operating conditions

			NE556		SA556		SE556		SE556C	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	4.5	16	4.5	16	4.5	18	4.5	16	V
VI	Input voltage (CONT, RESET, THRES, and TRIG)		Vcc		Vcc		Vcc		Vcc	V
IO	Output current		±200		±200		±200		±200	mA
TA	Operating free-air temperature	0	70	-40	85	-55	125	-55	125	°C

## electrical characteristics, V<sub>CC</sub> = 5 V to 15 V, T<sub>A</sub> = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS		NE	NE556, SA556, SE556C			SE556		
				MIN	TYP	MAX	MIN	TYP	MAX	
\/_	Threaded weltage lovel	V <sub>CC</sub> = 15 V		8.8	10	11.2	9.4	10	10.6	V
۷Ţ	Threshold voltage level	V <sub>CC</sub> = 5 V		2.4	3.3	4.2	2.7	3.3	4	v
IT	Threshold current (see Note 2)				30	250		30	250	nA
Varia		V <sub>CC</sub> = 15 V		4.5	5	5.6	4.8	5	5.2	V
VTRIG	Trigger voltage level	V <sub>CC</sub> = 5 V		1.1	1.67	2.2	1.45	1.67	1.9	v
ITRIG	Trigger current	TRIG at 0 V			0.5	2		0.5	0.9	μA
VRESET	Reset voltage level			0.3	0.7	1	0.3	0.7	1	V
1	Posot current	RESET at V <sub>CC</sub>			0.1	0.4		0.1	0.4	mA
RESET	Reset current	RESET at 0 V			-0.4	-1.5		-0.4	-1	
<b>I</b> DISCH	Discharge switch off-state current				20	100		20	100	nA
\/	Control voltage (open circuit)	V <sub>CC</sub> = 15 V		9	10	11	9.6	10	10.4	V
VCON1		V <sub>CC</sub> = 5 V		2.6	3.3	4	2.9	3.3	3.8	v
			I <sub>OL</sub> = 10 mA		0.1	0.25		0.1	0.15	<
		V <sub>CC</sub> = 15 V	I <sub>OL</sub> = 50 mA		0.4	0.75		0.4	0.5	
Voi			I <sub>OL</sub> = 100 mA		2	2.5		2	2.2	
VOL	Low-level output voltage		I <sub>OL</sub> = 200 mA		2.5			2.5		
		$V_{00} = 5 V$	I <sub>OL</sub> = 5 mA		0.1	0.25		0.1	0.15	
		VCC - 5 V	I <sub>OL</sub> = 8 mA		0.15	0.3		0.15	0.25	
		V00 - 15 V	$I_{OH} = -100 \text{ mA}$	12.75	13.3		13	13.3		
VOH	High-level output voltage	VCC = 15 V	$I_{OH} = -200 \text{ mA}$		12.5			12.5		V
		V <sub>CC</sub> = 5 V	$I_{OH} = -100 \text{ mA}$	2.75	3.3		3	3.3		
		Output high,	V <sub>CC</sub> = 15 V		20	30		20	24	
100	Supply current	No Load	$V_{CC} = 5 V$		6	12		6	10	nA
	Supply current	Output high, No load	V <sub>CC</sub> = 15 V		18	26		18	20	
			$V_{CC} = 5 V$		4	10		4	8	

NOTE 2: This parameter influences the maximum value of the timing resistors  $R_A$  and  $R_B$  in the circuit of Figure 1. For example, when  $V_{CC} = 5 \text{ V}$ , the maximum value is  $R = R_A + R_B \approx 3.4 \text{ M}\Omega$ , and for  $V_{CC} = 15 \text{ V}$ , the maximum value is  $\approx 10 \text{ M}\Omega$ .



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### operating characteristics, $V_{CC}$ = 5 V and 15 V

PARA	TEST	NE556, SA556, SE556C			SE556			UNIT	
		CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	
	Each timer, monostable§			1	3		0.5	1.5	%
Initial error of timing interval‡	Each timer, astable ${ m I}$	T <sub>A</sub> = 25°C		2.25			1.5		
	Timer 1 — Timer 2			±1			±0.5		
	Each timer, monostable§			50			30	100	
Iemperature coefficient of	Each timer, astable ${ m I}$	$I_{A} = MIN$ to MAX		150			90		ppm/°C
	Timer 1 — Timer 2			±10			±10		
	Each timer, monostable§			0.1	0.5		0.05	0.2	
Supply voltage sensitivity of timing interval	Each timer, astable $\P$	T <sub>A</sub> = 25°C		0.3			0.15		%/V
	Timer 1 — Timer 2			±0.2			±0.1		
Output pulse rise time		C <sub>L</sub> = 15 pF,		100	300		100	200	
Output pulse fall time		T <sub>A</sub> = 25°C		100	300		100	200	IIS

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>‡</sup> Timing interval error is defined as the difference between the measured value and the average value of a random sample from each process run. § Values specified are for a device in a monostable circuit similar to Figure 2, with component values as follow:  $R_A = 2 k\Omega$  to 100 k $\Omega$ ,  $C = 0.1 \mu F$ .

I Values specified are for a device in an astable circuit similar to Figure 1, with component values as follow:  $R_A = 2 R_2$  to 100 kg,  $C = 0.1 \mu F$ .

### **APPLICATION INFORMATION**



NOTE A: Bypassing the control voltage input to ground with a capacitor may improve operation. This should be evaluated for individual applications.





Figure 2. Circuit for Monostable Operation



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